

<b>Notice of References Cited</b>	Application/Control No. 10/712,415	Applicant(s)/Patent Under Reexamination MARIO ET AL.	
	Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,444,746	08-1995	Okamoto et al.	376/245
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.